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S1	20123	((irradiation or radiation or x-ray\$1 or xray\$1) near3 image\$1) and (edge\$1 or line\$1 or contour\$1) and (template\$1 or kernal\$1 or mask\$1 or reference\$1 or standard\$1)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2004/04/08 14:35
S2	175	((((irradiation or radiation or x-ray\$1 or xray\$1) near3 image\$1) and (edge\$1 or line\$1 or contour\$1) and (template\$1 or kernal\$1 or mask\$1 or reference\$1 or standard\$1)) and (scatter\$3 near3 line\$1)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2004/04/07 15:33
S3	5734	((irradiation or radiation or x-ray\$1 or xray\$1) near3 image\$1) and (edge\$1 or line\$1 or contour\$1) and (template\$1 or kernal\$1 or mask\$1)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2004/04/07 15:44
S4	38	((((irradiation or radiation or x-ray\$1 or xray\$1) near3 image\$1) and (edge\$1 or line\$1 or contour\$1) and (template\$1 or kernal\$1 or mask\$1)) and (scatter\$3 near3 line\$1)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2004/04/07 15:34
S5	3041	((irradiation or radiation or x-ray\$1 or xray\$1) near3 image\$1) and (edge\$1 or line\$1 or contour\$1) and (template\$1 or kernal\$1 or mask\$1) and densit\$3	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2004/04/07 15:46
S6	3449	((irradiation or radiation or x-ray\$1 or xray\$1) near3 image\$1) and ((detect\$4 or determin\$6 or locat\$6 or extract\$6) near3 (edge\$1 or line\$1 or contour\$1 or boundar\$3)) and (template\$1 or pattern\$1 or geometric)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2004/04/08 14:58
S7	126	((((irradiation or radiation or x-ray\$1 or xray\$1) near3 image\$1) and ((detect\$4 or determin\$6 or locat\$6 or extract\$6) near3 (edge\$1 or line\$1 or contour\$1 or boundar\$3)) and (template\$1 or pattern\$1 or geometric)) and score\$1	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2004/04/08 14:41
S8	956	((irradiation or radiation or x-ray\$1 or xray\$1) near3 image\$1) and (((detect\$4 or determin\$6 or locat\$6 or extract\$6) near3 (edge\$1 or line\$1 or contour\$1 or boundar\$3)) same (template\$1 or pattern\$1 or geometric))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2004/04/08 14:40

S9	40	(((irradiation or radiation or x-ray\$1 or xray\$1) near3 image\$1) and (((detect\$4 or determin\$6 or locat\$6 or extract\$6) near3 (edge\$1 or line\$1 or contour\$1 or boundar\$3)) same (template\$1 or pattern\$1 or geometric))) and score\$1	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2004/04/08 14:56
S10	134765	((detect\$4 or determin\$6 or locat\$6 or extract\$6) near3 (edge\$1 or line\$1 or contour\$1 or boundar\$3)) and (template\$1 or pattern\$1 or geometric)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2004/04/08 14:58
S11	3449	(((detect\$4 or determin\$6 or locat\$6 or extract\$6) near3 (edge\$1 or line\$1 or contour\$1 or boundar\$3)) and (template\$1 or pattern\$1 or geometric)) and ((irradiation or radiation or x-ray\$1 or xray\$1) near3 image\$1)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2004/04/08 14:59
S12	3355	(((detect\$4 or determin\$6 or locat\$6 or extract\$6) near3 (edge\$1 or line\$1 or contour\$1 or boundar\$3)) and (template\$1 or pattern\$1 or geometric)) and ((irradiation or radiation or x-ray\$1 or xray\$1) near3 image\$1) ) and (pixel\$1 or point\$1 or feature\$1 or characteristic\$1)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2004/04/08 15:00
S13	3193	(((detect\$4 or determin\$6 or locat\$6 or extract\$6) near3 (edge\$1 or line\$1 or contour\$1 or boundar\$3)) and (template\$1 or pattern\$1 or geometric)) and ((irradiation or radiation or x-ray\$1 or xray\$1) near3 image\$1) ) and (pixel\$1 or point\$1)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2004/04/08 15:00
S14	125	(((detect\$4 or determin\$6 or locat\$6 or extract\$6) near3 (edge\$1 or line\$1 or contour\$1 or boundar\$3)) and (template\$1 or pattern\$1 or geometric)) and ((irradiation or radiation or x-ray\$1 or xray\$1) near3 image\$1) ) and (pixel\$1 or point\$1)) and score\$1	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2004/04/08 15:01
S15	5751	382/128,132,172,190,195,199,200,201,202,203,204,205,217.ccls.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2004/05/05 15:26
S16	1977	382/128,132,172,190,195,199,200,201,202,203,204,205,217.ccls. and ((detect\$6 or determin\$6 or extract\$6 or locat\$5) near3 (edge\$1 or contour\$1 or boundar\$3))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2004/04/09 10:24

S17	1411	(382/128,132,172,190,195,199,200, 201,202,203,204,205,217.ccls. and ((detect\$6 or determin\$6 or extract\$6 or locat\$5) near3 (edge\$1 or contour\$1 or boundar\$3)) ) and (template\$1 or kernal\$1 or geometric or pattern\$1)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2004/04/09 10:26
S18	1853	(382/128,132,172,190,195,199,200, 201,202,203,204,205,217.ccls. and ((detect\$6 or determin\$6 or extract\$6 or locat\$5) near3 (edge\$1 or contour\$1 or boundar\$3)) ) and (pixel\$1 or point\$1)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2004/04/09 10:26
S19	1356	((382/128,132,172,190,195,199,200, 201,202,203,204,205,217.ccls. and ((detect\$6 or determin\$6 or extract\$6 or locat\$5) near3 (edge\$1 or contour\$1 or boundar\$3)) ) and (template\$1 or kernal\$1 or geometric or pattern\$1)) and (pixel\$1 or point\$1)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2004/04/09 10:26
S20	749	((382/128,132,172,190,195,199,200, 201,202,203,204,205,217.ccls. and ((detect\$6 or determin\$6 or extract\$6 or locat\$5) near3 (edge\$1 or contour\$1 or boundar\$3)) ) and (template\$1 or kernal\$1 or geometric or pattern\$1)) and ((near\$2or adjacent\$3 or neighbor\$3 or close\$4) near3 (pixel\$1 or point\$1))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2004/04/09 10:30
S21	332	((382/128,132,172,190,195,199,200, 201,202,203,204,205,217.ccls. and ((detect\$6 or determin\$6 or extract\$6 or locat\$5) near3 (edge\$1 or contour\$1 or boundar\$3)) ) and (template\$1 or kernal\$1 or geometric or pattern\$1)) and ((near\$2or adjacent\$3 or neighbor\$3 or close\$4) near3 (pixel\$1 or point\$1)) ) and densit\$3	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2004/04/09 10:28
S22	184	((382/128,132,172,190,195,199,200, 201,202,203,204,205,217.ccls. and ((detect\$6 or determin\$6 or extract\$6 or locat\$5) near3 (edge\$1 or contour\$1 or boundar\$3)) ) and (template\$1 or kernal\$1 or geometric or pattern\$1)) and ((near\$2or adjacent\$3 or neighbor\$3 or close\$4) near3 (pixel\$1 or point\$1)) ) and (radiation or x-ray\$1 or xray\$1 or irradiation)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2004/04/09 10:34

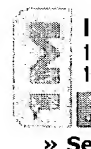
S23	57	(((((382/128,132,172,190,195,199,200,201,202,203,204,205,217.ccls. and ((detect\$6 or determin\$6 or extract\$6 or locat\$5) near3 (edge\$1 or contour\$1 or boundar\$3)) ) and (template\$1 or kernal\$1 or geometric or pattern\$1)) and ((near\$2or adjacent\$3 or neighbor\$3 or close\$4) near3 (pixel\$1 or point\$1)) ) and (radiation or x-ray\$1 or xray\$1 or irradiation)) and (((similarit\$4 or feature\$1) near3 (table\$1 or list\$1 or value\$1)) or scor\$3)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2004/04/09 11:02
S24	4	"4851678".pn.",4962539".pn.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2004/04/09 11:02
S25	5807	382/128,132,172,190,195,199,200,201,202,203,204,205,217.ccls.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2004/05/05 15:27
S26	839	382/128,132,172,190,195,199,200,201,202,203,204,205,217.ccls. and ((radiation or x-ray\$1 or xray\$1) near3 imag\$4)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2004/05/05 15:28
S27	1140	382/128,132,172,190,195,199,200,201,202,203,204,205,217.ccls. and ((radiation or x-ray\$1 or xray\$1 or medical) near3 imag\$4)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2004/05/05 15:28
S28	468	(382/128,132,172,190,195,199,200,201,202,203,204,205,217.ccls. and ((radiation or x-ray\$1 or xray\$1 or medical) near3 imag\$4)) and ((edge or edges or line or lines) near3 (detect\$4 or locat\$4 or determin\$6))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2004/05/05 15:31
S29	177	(382/128,132,172,190,195,199,200,201,202,203,204,205,217.ccls. and ((radiation or x-ray\$1 or xray\$1 or medical) near3 imag\$4)) and (((edge or edges or line or lines) near3 (detect\$4 or locat\$4 or determin\$6)) same (template\$1 or kernal\$1 or standard\$1 or pattern\$1 or mask\$1))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2004/05/05 15:32

S30	246	(382/128,132,172,190,195,199,200,201,202,203,204,205,217.ccls. and ((radiation or x-ray\$1 or xray\$1 or medical) near3 imag\$4)) and (((edge or edges or line or lines) near3 (detect\$4 or locat\$4 or determin\$6)) same (template\$1 or kernal\$1 or standard\$1 or pattern\$1 or mask\$1 or reference\$1))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2004/11/28 14:19
S31	4	"5343390".pn.",5962539".pn.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2004/05/14 16:18
S32	8496	382/100,128,132,172,190,195,199,200,201,202,203,204,205,217,243,266.ccls.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2004/11/28 14:21
S33	303	S32 and (line\$1 or segment\$6 or edg\$5 or contour\$) and pixel\$1 and ((radiation or irradiation) near4 imag\$5)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2004/11/28 14:24
S34	37	S33 and (irradiation near5 (field\$1 or area\$1 or section\$5 or segment\$4 or region\$4))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2004/11/28 14:43
S35	94	S32 and (irradiation near5 (field\$1 or area\$1 or section\$5 or segment\$4 or region\$4))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2004/11/28 14:43
S36	11	S35 and ((pixel\$ near5 (densit\$ or intens\$5 or value\$4 or score\$1)) same (add\$3 or sum\$7))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2004/11/28 14:46
S37	615	(radiation near5 image\$1) and ((pixel\$ near5 (densit\$ or intens\$5 or value\$4 or score\$1)) same (add\$3 or sum\$7))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2004/11/28 14:47
S38	759	(radiation near5 image\$1) and ((pixel\$ near5 (densit\$ or intens\$5 or value\$4 or score\$1)) same (add\$3 or sum\$7 or comb\$6))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2004/11/28 14:48

S39	18	S38 and ((detect\$5 or recogniz\$6 or determin\$7) near6 (irradiation near4 (section\$ or lin\$3 or area\$ or region\$4 or segment\$5 or field\$4)))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2004/11/28 14:51
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## Results Key:

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**1 Evaluation of a structured cesium iodide film for radiation imaging purposes**
*Jing, T.; Goodman, C.A.; Cho, G.; Drewery, J.; Hong, W.S.; Lee, H.; Kaplan, M.; Miresghhi, A.; Perez-Mendez, V.; Wildermuth, D.;*

Nuclear Science Symposium and Medical Imaging Conference, 1993., 1993 IEEE Conference Record. , 31 Oct.-6 Nov. 1993

Pages:1878 - 1882 vol.3

[\[Abstract\]](#)    [\[PDF Full-Text \(404 KB\)\]](#)    **IEEE CNF**
**2 New results on DEPFET pixel detectors for radiation imaging and high energy particle detection**
*Wermes, N.; Andricek, L.; Fischer, P.; Heinzinger, K.; Herrmann, S.; Karagou, M.; Kohrs, R.; Kruger, H.; Lutz, G.; Lechner, P.; Peric, I.; Porro, M.; Richter, I.; Schaller, G.; Schnecke-Radau, M.; Schopper, F.; Soltau, H.; Struder, L.; Trim, M.; Ulrici, J.; Treis, J.;*

 Nuclear Science, IEEE Transactions on , Volume: 51 , Issue: 3 , June 2004  
 Pages:1121 - 1128

[\[Abstract\]](#)    [\[PDF Full-Text \(616 KB\)\]](#)    **IEEE JNL**
**3 An asynchronous pixel architecture for simultaneous radiation imaging and spectroscopy on a real-time basis**
*Kapnistis, C.; Misiakos, K.; Haralabidis, N.; Kyriakis-Bitaros, D.;*

 Nuclear Science, IEEE Transactions on , Volume: 49 , Issue: 4 , Aug. 2002  
 Pages:1802 - 1807

[\[Abstract\]](#)    [\[PDF Full-Text \(244 KB\)\]](#)    **IEEE JNL**
**4 A novel radiation imaging sensor based on self-activated pixels**



*Kavadias, S.; Misiakos, K.; Loukas, D.;*  
Nuclear Science, IEEE Transactions on , Volume: 42 , Issue: 3 , June 1995  
Pages:155 - 162

[\[Abstract\]](#) [\[PDF Full-Text \(636 KB\)\]](#) IEEE JNL

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**5 New results on DEPFET pixel detectors for radiation imaging and high energy particle detection**

*Wermes, N.; Andricek, L.; Fischer, P.; Harter, M.; Herrmann, S.; Karagounis, Kohrs, R.; Kruger, H.; Lutz, G.; Lechner, P.; Peric, I.; Porro, M.; Richter, R.; Soltan, H.; Struder, L.; Trimpl, M.; Ulrici, J.; Treis, J.;*  
Nuclear Science Symposium Conference Record, 2003 IEEE , Volume: 1 , 19-: Oct. 2003  
Pages:325 - 330 Vol.1

[\[Abstract\]](#) [\[PDF Full-Text \(722 KB\)\]](#) IEEE CNF

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**6 Radiation imaging with 2D a-Si sensor arrays**

*Fujieda, I.; Nelson, S.; Street, R.A.; Weisfield, R.L.;*  
Nuclear Science Symposium and Medical Imaging Conference, 1991., Conference Record of the 1991 IEEE , 2-9 Nov. 1991  
Pages:1882 - 1886 vol.3

[\[Abstract\]](#) [\[PDF Full-Text \(404 KB\)\]](#) IEEE CNF

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**7 Preliminary test of Medisoft 4: control software for the Medipix2 readout chip**

*Conti, M.; Maiorino, M.; Mettivier, G.; Montesi, M.C.; Russo, P.;*  
Nuclear Science, IEEE Transactions on , Volume: 50 , Issue: 4 , Aug. 2003  
Pages:869 - 877

[\[Abstract\]](#) [\[PDF Full-Text \(1541 KB\)\]](#) IEEE JNL

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**8 Radiation imaging with 2D a-Si sensor arrays**

*Fujieda, I.; Nelson, S.; Street, R.A.; Weisfield, R.L.;*  
Nuclear Science, IEEE Transactions on , Volume: 39 , Issue: 4 , Aug 1992  
Pages:1056 - 1062

[\[Abstract\]](#) [\[PDF Full-Text \(668 KB\)\]](#) IEEE JNL

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**9 Report from the 5<sup>th</sup>/ International Workshop on Radiation Imaging Detectors**

*Ludwig, J.;*  
Nuclear Science Symposium Conference Record, 2003 IEEE , Volume: 1 , 19-: Oct. 2003  
Pages:117 - 119 Vol.1

[\[Abstract\]](#) [\[PDF Full-Text \(1118 KB\)\]](#) IEEE CNF

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**10 Preliminary test of Medisoft 4: control software for the Medipix2 readout chip**

*Maionino, M.; Mettivier, G.; Montesi, M.C.; Russo, P.;*  
Nuclear Science Symposium Conference Record, 2002 IEEE , Volume: 1 , 10-:

Nov. 2002  
Pages:189 - 193 vol.1

[\[Abstract\]](#) [\[PDF Full-Text \(895 KB\)\]](#) [IEEE CNF](#)

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**11 A pixel segmented silicon strip detector for ultra fast shaping at low noise and low power consumption**

*Misiakos, K.; Kavadias, S.;*

Nuclear Science Symposium and Medical Imaging Conference Record, 1995.,  
IEEE , Volume: 1 , 21-28 Oct. 1995

Pages:18 - 22 vol.1

[\[Abstract\]](#) [\[PDF Full-Text \(388 KB\)\]](#) [IEEE CNF](#)

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**12 Portable system for imaging of /spl alpha/, and X-ray sources with silicon pixel detectors and Medipix1 readout**

*Bertolucci, E.; Boerkamp, T.; Maiorino, M.; Mettivier, G.; Montesi, M.C.; Russo,*

Nuclear Science, IEEE Transactions on , Volume: 49 , Issue: 4 , Aug. 2002

Pages:1845 - 1850

[\[Abstract\]](#) [\[PDF Full-Text \(573 KB\)\]](#) [IEEE JNL](#)

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**13 Analysis of images of radiation due to plasma-limiter interaction**

*Peterson, B.J.; Ashikawa, N.; Kostrioukov, A.Yu.; Nishimura, K.; Kojima, H.; S. S.;*

Plasma Science, IEEE Transactions on , Volume: 30 , Issue: 1 , Feb. 2002

Pages:52 - 53

[\[Abstract\]](#) [\[PDF Full-Text \(278 KB\)\]](#) [IEEE JNL](#)

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**14 A pixel segmented silicon strip detector for ultra fast shaping at low noise and low power consumption**

*Misiakos, K.; Kavadias, S.;*

Nuclear Science, IEEE Transactions on , Volume: 43 , Issue: 3 , June 1996

Pages:1102 - 1106

[\[Abstract\]](#) [\[PDF Full-Text \(396 KB\)\]](#) [IEEE JNL](#)

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**15 Robust window discriminator for photon-counting pixel detectors**

*Oelmann, B.; Abdalla, M.; O'Nils, M.;*

Optoelectronics, IEE Proceedings- , Volume: 149 , Issue: 2 , April 2002

Pages:65 - 69

[\[Abstract\]](#) [\[PDF Full-Text \(371 KB\)\]](#) [IEEE JNL](#)

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1 **Optical transition radiation imaging of intense proton beams at FNA**  
*Scarpine, V.E.; Lumpkin, A.H.; Schappert, W.; Tassotto, G.R.;*  
 Nuclear Science, IEEE Transactions on , Volume: 51 , Issue: 4 , Aug. 2004  
 Pages:1529 - 1532

[Abstract] [PDF Full-Text (296 KB)] IEEE JNL

2 **Terahertz radiation imaging of vortices penetrated into YBCO thin film**  
*Tonouchi, M.; Moto, A.; Yamashita, M.; Hangyo, M.;*  
 Applied Superconductivity, IEEE Transactions on , Volume: 11 , Issue: 1 , Mar 2001  
 Pages:3230 - 3233

[Abstract] [PDF Full-Text (360 KB)] IEEE JNL

3 **A pixel segmented silicon strip detector for ultra fast shaping at low noise and low power consumption**  
*Misiakos, K.; Kavadias, S.;*  
 Nuclear Science Symposium and Medical Imaging Conference Record, 1995.,  
 IEEE , Volume: 1 , 21-28 Oct. 1995  
 Pages:18 - 22 vol.1

[Abstract] [PDF Full-Text (388 KB)] IEEE CNF

4 **New results on DEPFET pixel detectors for radiation imaging and high energy particle detection**  
*Wermes, N.; Andricek, L.; Fischer, P.; Heinzinger, K.; Herrmann, S.; Karagou,  
 M.; Kohrs, R.; Kruger, H.; Lutz, G.; Lechner, P.; Peric, I.; Porro, M.; Richter, I.  
 Schaller, G.; Schnecke-Radau, M.; Schopper, F.; Soltau, H.; Struder, L.; Trim,  
 M.; Ulrici, J.; Treis, J.;*

Nuclear Science, IEEE Transactions on , Volume: 51 , Issue: 3 , June 2004  
Pages:1121 - 1128

[\[Abstract\]](#) [\[PDF Full-Text \(616 KB\)\]](#) **IEEE JNL**

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**5 A pixel segmented silicon strip detector for ultra fast shaping at low noise and low power consumption**

*Misiakos, K.; Kavadias, S.;*

Nuclear Science, IEEE Transactions on , Volume: 43 , Issue: 3 , June 1996  
Pages:1102 - 1106

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**6 A novel radiation imaging sensor based on self-activated pixels**

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**7 New results on DEPFET pixel detectors for radiation imaging and high energy particle detection**

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## 3 Development of an orthogonal-stripe CdZnTe gamma radiation imaging spectrometer

Macri, J.R.; Apotovsky, B.A.; Butler, J.F.; Cherry, M.L.; Dann, B.K.; Drake, A.; Doty, F.P.; Guzik, T.G.; Larson, K.; Mayer, M.; McConnell, M.L.; Ryan, J.M.;

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